


<b>Search Notes</b>  	<b>Application/Control No.</b>  10589623	<b>Applicant(s)/Patent Under Reexamination</b>  WEISS ET AL.
	<b>Examiner</b>  JENNIFER M KIM	<b>Art Unit</b>  1628

SEARCHED			
Class	Subclass	Date	Examiner
514	454, 568, 734	6/8/2010	jmk
	Updated	2/14/2011	jmk

SEARCH NOTES		
Search Notes	Date	Examiner
Inventores search; STIC	6/8/2010	jmk
Updated; see search notes	2/14/2011	jmk

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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